

<b>Notice of References Cited</b>	Application/Control No. 10/523,524	Applicant(s)/Patent Under Reexamination SEITOH ET AL.	
	Examiner EDMUND H. LEE	Art Unit 1791	Page 1 of 1

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*	B	US-5,783,133	07-1998	Hara et al.	264/261
*	C	US-5,846,470	12-1998	Funatsu et al.	264/275
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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